

TOSHIBA CCD IMAGE SENSOR CCD (Charge Coupled Device)

TCD2553AD

The TCD2553AD is a high sensitive and low dark current 5340 × 3 elements linear image sensor.

The sensor can be used for image scanner. The device contains a row of 5340 elements × 3 line photodiodes, which provide a 24 line/mm (600DPI) across a A4 size paper. The device is operated by 5 V (Pulse), and 12 V power supply.

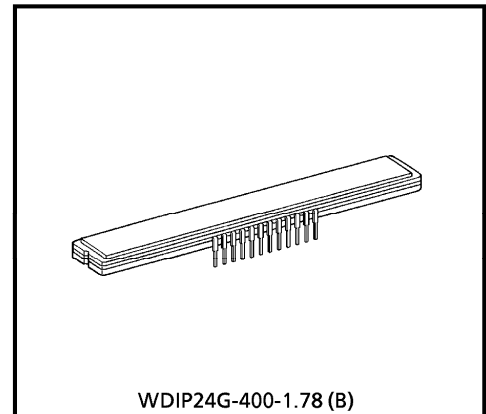
FEATURES

- Number of Image Sensing Elements : 5340 × 3
- Image Sensing Element Size : 8 μm by 8 μm on 8 μm centers
- Photo Sensing Region : High sensitive and low dark current PN photodiode
- Clock : 2 phase (5 V)
- Power Supply : 12 V (DC)
- Package : 24 pin CERDIP
- Distance Between Photodiode Array : 64 μm, 8 line
- Internal Circuit : Electrical Shutter Function S/H, Clamp Circuit

MAXIMUM RATINGS (Note 1)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Clock Pulse Voltage	$V\phi$	- 0.3~8	V
Shift Pulse Voltage	V_{SH}		V
Reset Pulse Voltage	V_{RS}		V
Clamp Pulse Voltage	V_{CP}		V
Sample and Hold Voltage	V_{SP}		V
Electrical Shutter Voltage	V_{ICG}		V
Power Supply	V_{OD}	- 0.3~15	V
Digital Power Supply	V_{DD}		V
Operating Temperature	T_{opr}	0~60	°C
Storage Temperature	T_{stg}	- 25~85	°C

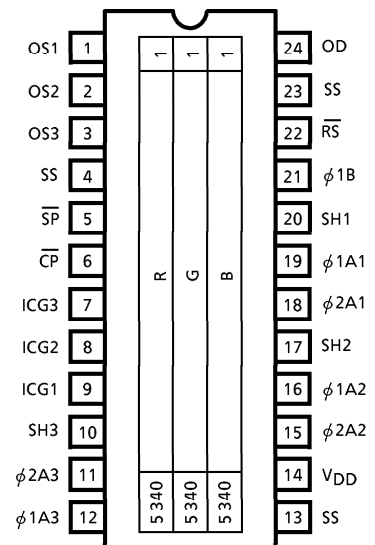
(Note 1) : All voltage are with respect to SS terminals (Ground).



WDIP24G-400-1.78 (B)

Weight : 8.0 g (Typ.)

PIN CONNECTIONS

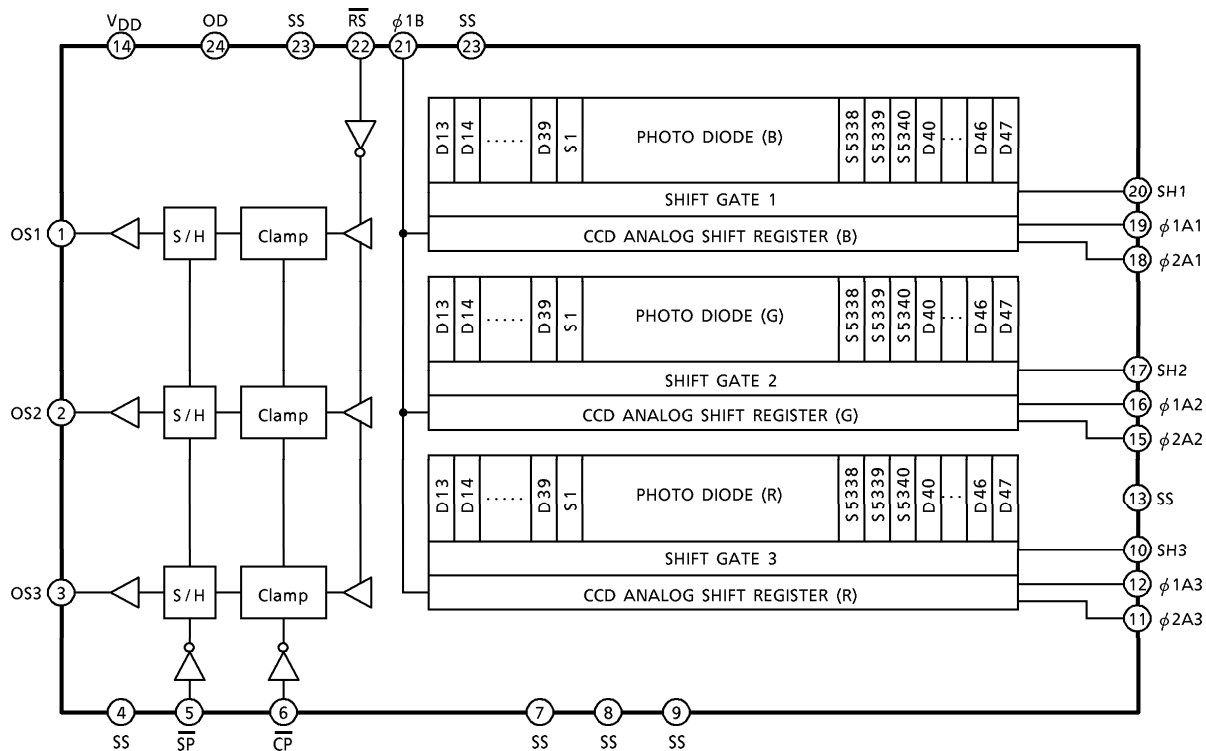


(TOP VIEW)

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CIRCUIT DIAGRAM



PIN NAMES

PIN No.	SYMBOL	NAME	PIN No.	SYMBOL	NAME
1	OS1	Signal Output 1 (Blue)	13	SS	Ground
2	OS2	Signal Output 2 (Green)	14	V _{DD}	Power (Digital)
3	OS3	Signal Output 3 (Red)	15	φ2A2	Clock 2 (Phase 2)
4	SS	Ground	16	φ1A2	Clock 2 (Phase 1)
5	SP	Sample and Hold Gate	17	SH2	Shift Gate 2
6	CP	Clamp Gate	18	φ2A1	Clock 1 (Phase 2)
7	SS	Ground	19	φ1A1	Clock 1 (Phase 1)
8	SS	Ground	20	SH1	Shift Gate 1
9	SS	Ground	21	φ1B	Final Stage Clock (Phase 1)
10	SH3	Shift Gate 3	22	RS	Reset Gate
11	φ2A3	Clock 3 (Phase 2)	23	SS	Ground
12	φ1A3	Clock 3 (Phase 1)	24	OD	Power (Analog)

OPTICAL / ELECTRICAL CHARACTERISTICS

(Ta = 25°C, V_{OD} = V_{DD} = 12 V, V_φ = V_{SH} = V_{RS} = 5 V (PULSE), f_φ = 1 MHz, f_{RS} = 1 MHz, t_{INT} = 10 ms, LIGHT SOURCE = A LIGHT SOURCE + CM500S FILTER (t = 1 mm), LOAD RESISTANCE = 100 kΩ)

CHARACTERISTIC		SYMBOL	MIN.	TYP.	MAX.	UNIT	NOTE
Sensitivity	Red	R (R)	4.6	6.6	8.6	V / lx·s	(Note 2)
	Green	R (G)	5.6	8.1	10.5		
	Blue	R (B)	3.9	5.6	7.3		
Photo Response Non Uniformity		PRNU (1)	—	10	20	%	(Note 3)
		PRNU (3)	—	3	12	mV	(Note 4)
Image Lag		IL	—	1	—	%	(Note 5)
Saturation Output Voltage		V _{SAT}	2.0	2.5	—	V	(Note 6)
Saturation Exposure		SE	—	0.31	—		(Note 7)
Dark Signal Voltage		V _{DRK}	—	3	9	mV	(Note 8)
Dark Signal Non Uniformity		DSNU	—	4	12	mV	(Note 8)
DC Power Dissipation		P _D	—	200	400	mW	
Total Transfer Efficiency		TTE	92	—	—	%	
Output Impedance		Z _O	—	—	1	kΩ	
DC Compensation Output Voltage		V _{OS}	3	5	7	V	(Note 9)
Random Noise		N _{Dσ}	—	0.8	—	mV	(Note 10)
Reset Noise		V _{RSN}	—	200	—	mV	(Note 9)

(Note 2) : Responsivity is defined for each color of signal outputs average when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

(Note 3) : PRNU (1) is defined for each color on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

$$\text{PRNU (1)} = \frac{\Delta\bar{x}}{\bar{x}} \times 100 (\%)$$

When \bar{x} is average of total signal output and $\Delta\bar{x}$ is the maximum deviation from \bar{x} . The amount of incident light is shown below.

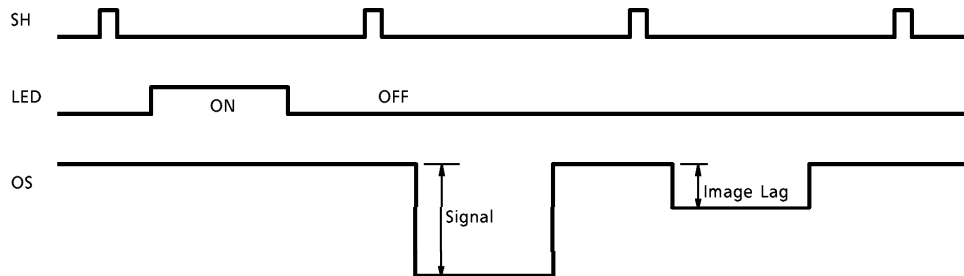
$$\text{Red} = 1/2 \cdot \text{SE}$$

$$\text{Green} = 1/2 \cdot \text{SE}$$

$$\text{Blue} = 1/4 \cdot \text{SE}$$

(Note 4) : PRNU (3) is defined as maximum voltage with next pixel, where measured 5% of SE (Typ.).

(Note 5) : Image Lag is defined as follows.



(Note 6) : V_{SAT} is defined as minimum saturation output of all effective pixels.

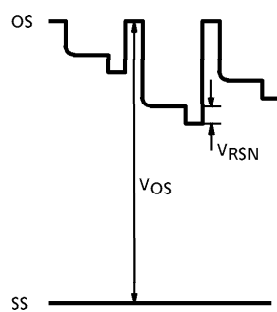
(Note 7) : Definition of SE

$$SE = \frac{V_{SAT}}{R_G} (lx \cdot s)$$

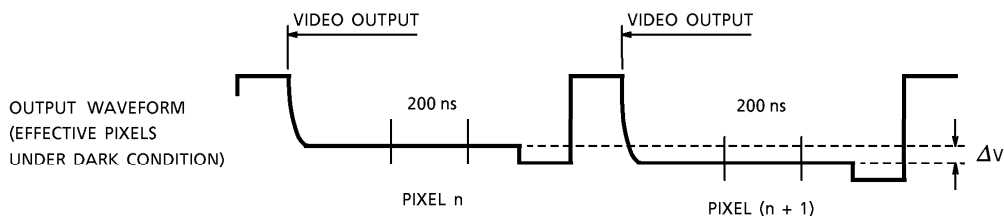
(Note 8) : V_{DRK} is defined as average dark signal voltage of all effective pixels.
 $DSNU$ is defined as different voltage between V_{DRK} and V_{MDK} , when V_{MDK} is maximum dark signal voltage.



(Note 9) : DC signal output voltage is defined as follows.
 Reset Noise Voltage is defined as follows.



(Note 10) : Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark conditions) calculated by the following procedure.



- 1) Two adjacent pixels (pixel n and n + 1) in one reading are fixed as measurement points.
- 2) Each of the output level at video output periods averaged over 200 ns period to get V_n and $V(n + 1)$.
- 3) $V(n + 1)$ is subtracted from V_n to get ΔV .

$$\Delta V = V_n - V(n + 1)$$
- 4) The standard deviation of ΔV is calculated after procedure 2) and 3) are repeated 30 times (30 readings).

$$\overline{\Delta V} = \frac{1}{30} \sum_{i=1}^{30} |\Delta V_i| \quad \sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} (|\Delta V_i| - \overline{\Delta V})^2}$$

- 5) Procedure 2), 3) and 4) are repeated 10 times to get sigma value.
- 6) 10 sigma values are averaged.

$$\overline{\sigma} = \frac{1}{10} \sum_{j=1}^{10} \sigma_j$$

- 7) $\overline{\sigma}$ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify random noise as follows.

$$ND \sigma = \frac{1}{\sqrt{2}} \overline{\sigma}$$

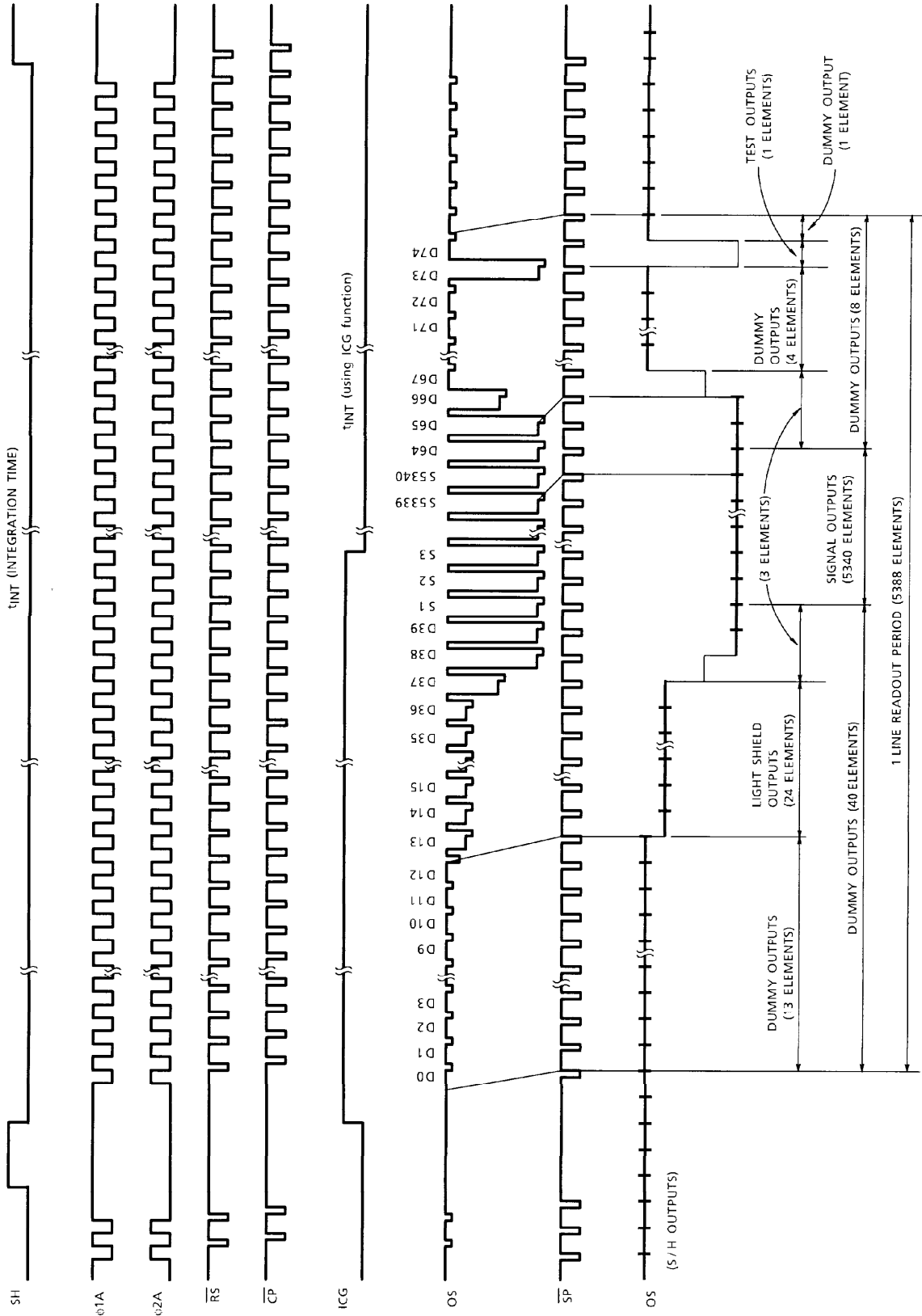
OPERATING CONDITION

CHARACTERISTIC		SYMBOL	MIN.	TYP.	MAX.	UNIT
Clock Pulse Voltage	"H" Level	V_{ϕ}	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Shift Pulse Voltage	"H" Level	V_{SH}	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Reset Pulse Voltage	"H" Level	$V_{\overline{RS}}$	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Clamp Pulse Voltage	"H" Level	$V_{\overline{CP}}$	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Sample and Hold Pulse Voltage	"H" Level	$V_{\overline{SP}}$	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Electrical Shutter Voltage	"H" Level	V_{ICG}	4.5	5.0	5.5	V
	"L" Level		0	0	0.3	
Digital Power Supply		V_{DD}	11.4	12.0	13.0	V
Power Supply		V_{OD}	11.4	12.0	13.0	V

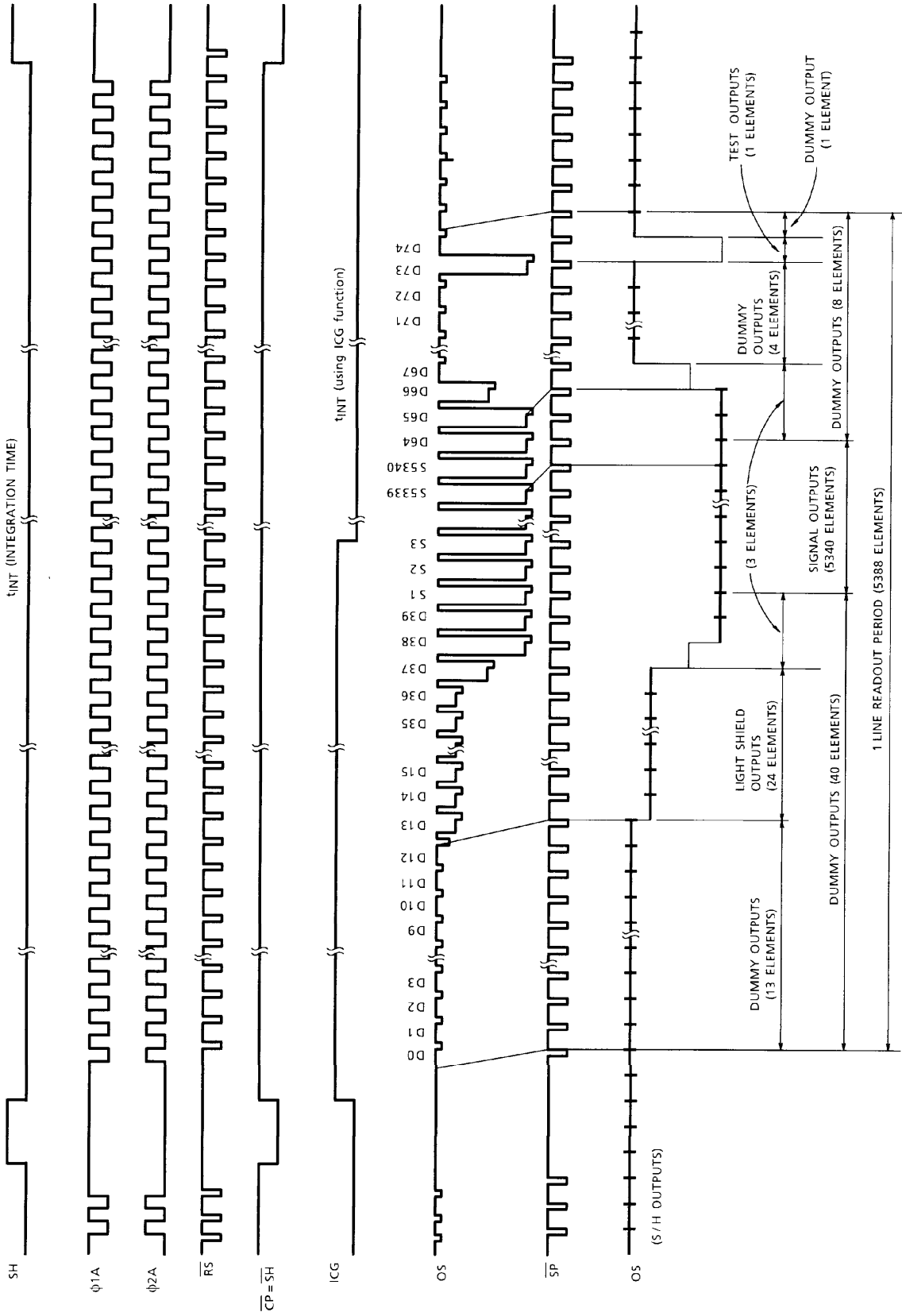
CLOCK CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Clock Pulse Frequency	f_{ϕ}	0.3	1	5	MHz
Reset Pulse Frequency	$f_{\overline{RS}}$	0.3	1	5	MHz
Sample and Hold Pulse Frequency	$f_{\overline{SP}}$	0.3	1	5	MHz
Clock Capacitance	$C_{\phi A}$	—	400	550	pF
Final Stage Clock Capacitance	$C_{\phi B}$	—	15	30	pF
Shift Gate Capacitance	C_{SH}	—	20	30	pF
Reset Gate Capacitance	$C_{\overline{RS}}$	—	20	30	pF
Clamp Gate Capacitance	$C_{\overline{CP}}$	—	20	30	pF
Sample and Hold Gate Capacitance	$C_{\overline{SP}}$	—	20	30	pF
ICG Gate Capacitance	C_{ICG}	—	20	30	pF

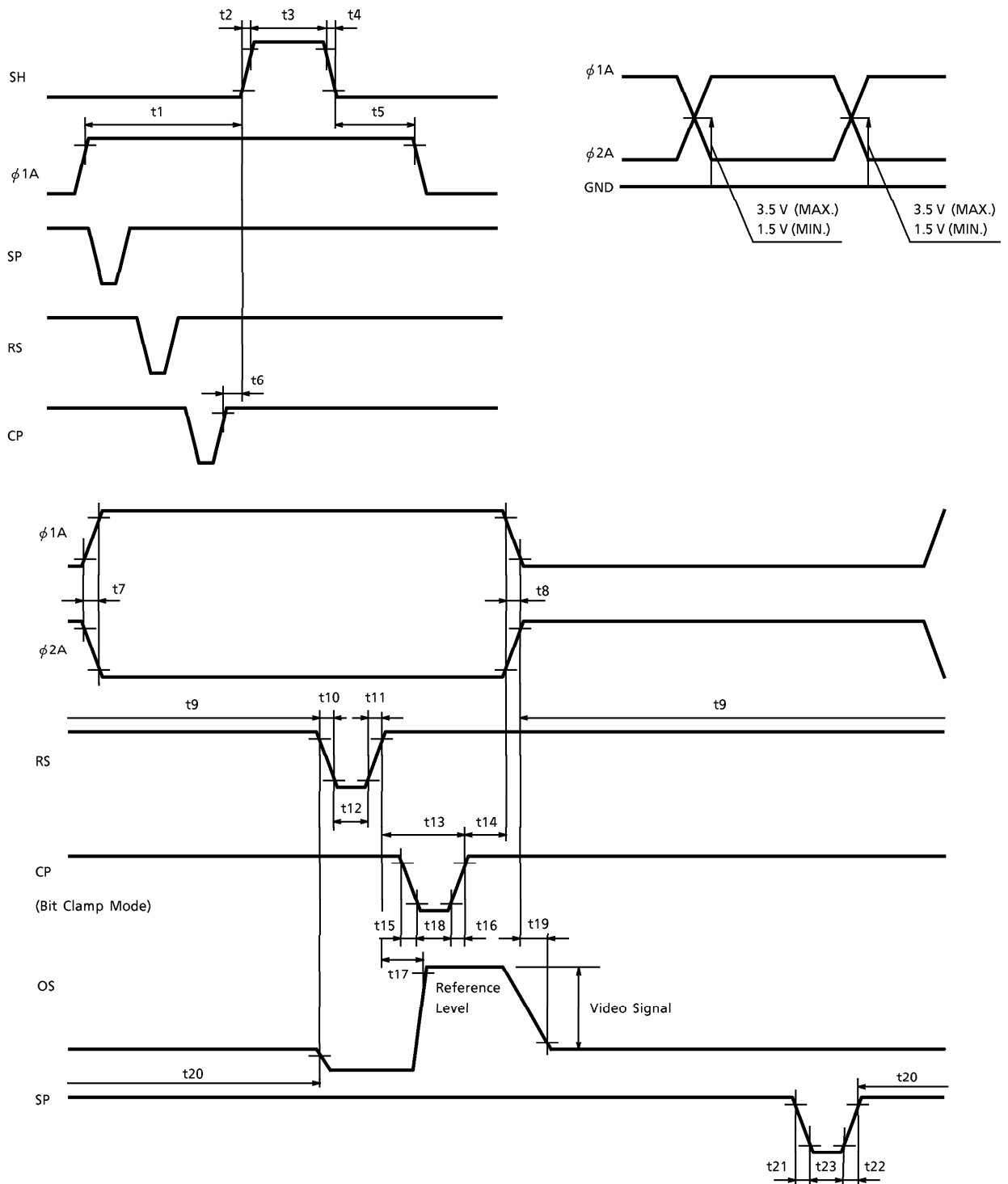
TIMING CHART (BIT CLAMP MODE)



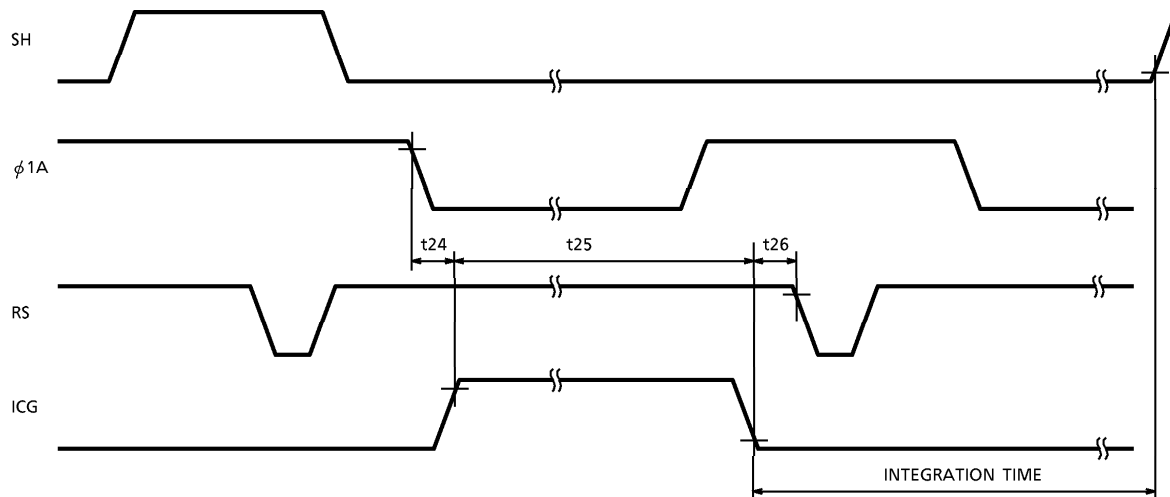
TIMING CHART (LINE CLAMP MODE)



TIMING REQUIREMENTS



TIMING REQUIREMENTS

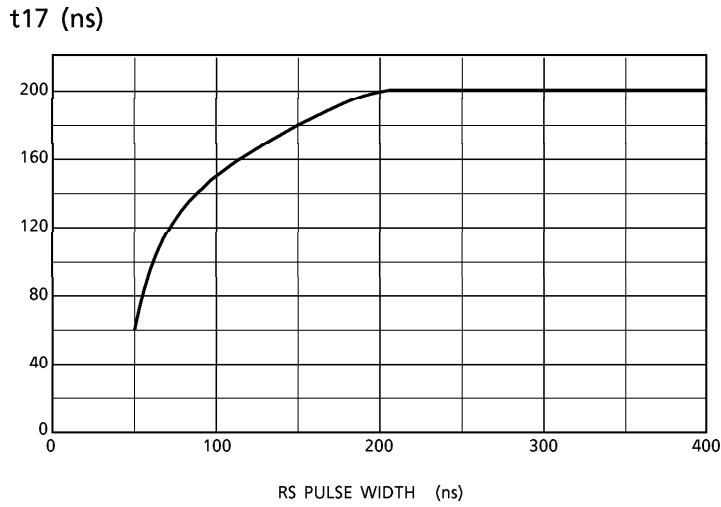


CHARACTERISTIC	SYMBOL	MIN.	TYP. (Note 11)	MAX.	UNIT
Pulse Timing of SH and φ1A	t1	120	1000	—	ns
	t5	800	1000	—	
SH Pulse Rise Time, Fall Time	t2, t4	0	50	—	ns
SH Pulse Width	t3	3000	5000	—	ns
Pulse Timing of SH and CP	t6	0	500	—	ns
φ1A, φ2A Pulse Rise Time, Fall Time	t7, t8	0	50	—	ns
Pulse Timing of φ1A and RS	t9	100	—	—	ns
RS Pulse Rise Time, Fall Time	t10, t11	0	20	—	ns
RS Pulse Width	t12	40	100	—	ns
CP Pulse Rise Time, Fall Time	t15, t16	0	20	—	ns
Pulse Timing of RS and CP	t13	120	200	—	ns
Pulse Timing of φ1A, φ2A and CP	t14	10	50	—	ns
Pulse Timing of RS and RS-noise	t17	(Note 13)	—	—	ns
CP Pulse Width	t18	40	100	—	ns
SP Pulse Rise Time, Fall Time	t21, t22	—	20	—	ns
SP Pulse Width	t23	40	100	—	ns
Pulse Timing of RS and SP	t20	0	20	—	ns
Video Data Delay Time (Note 12)	t19	—	80	—	ns
Pulse Timing of φ1A and ICG	t24	0	10	—	ns
ICG Pulse Width	t25	200	—	—	μs
Pulse Timing of ICG and RS	t26	100	—	—	ns

(Note 11) : TYP. is the case of $f_{RS} = 1.0$ MHz.

(Note 12) : Load Resistance is 100 kΩ.

(Note 13) :



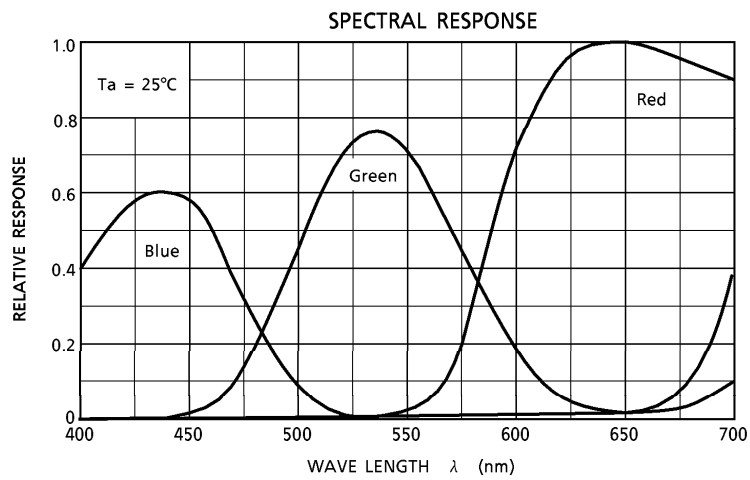
APPLICATION NOTE

FUNCTION	ON	OFF
Sample & Hold Function	SP Pulse	SP = Low
Electrical Shutter Function	ICG Pulse	ICG = Low

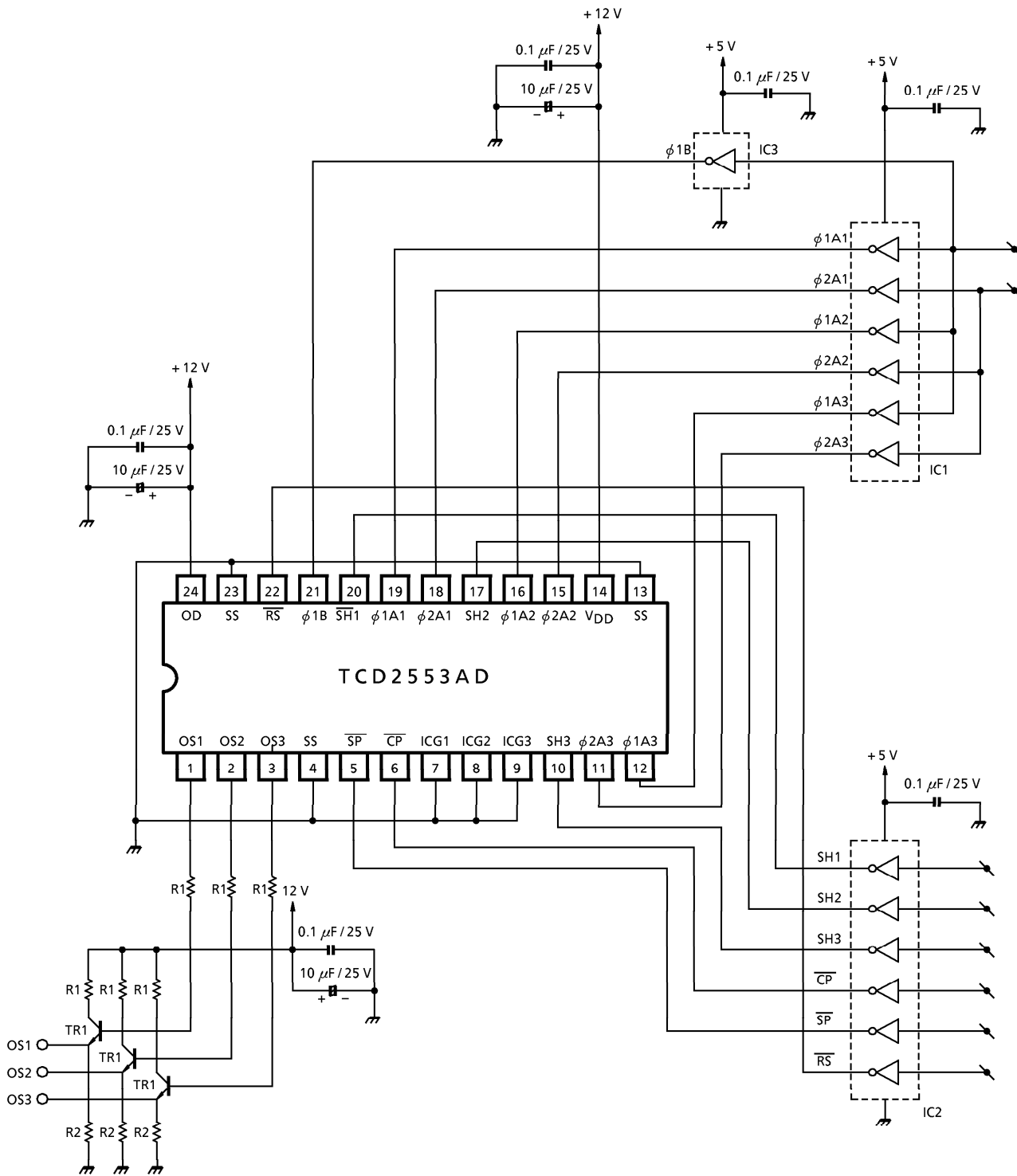
CLAMP MODE

CLAMP MEANS	CP INPUT PULSE
Bit Clamp	CP Pulse
Line Clamp	CP = SH

TYPICAL SPECTRAL RESPONSE



TYPICAL DRIVE CIRCUIT



- IC1, 2, 3 : TC74HC04AP
- TR1 : 2SC1815-Y
- R1 : 150 Ω
- R2 : 1500 Ω

CAUTION**1. Window Glass**

The dust and stain on the glass window of the package degrade optical performance of CCD sensor.

Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N₂.

Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

2. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

3. Incident Light

CCD sensor is sensitive to infrared light.

Note that infrared light component degrades resolution and PRNU of CCD sensor.

4. Lead Frame Forming

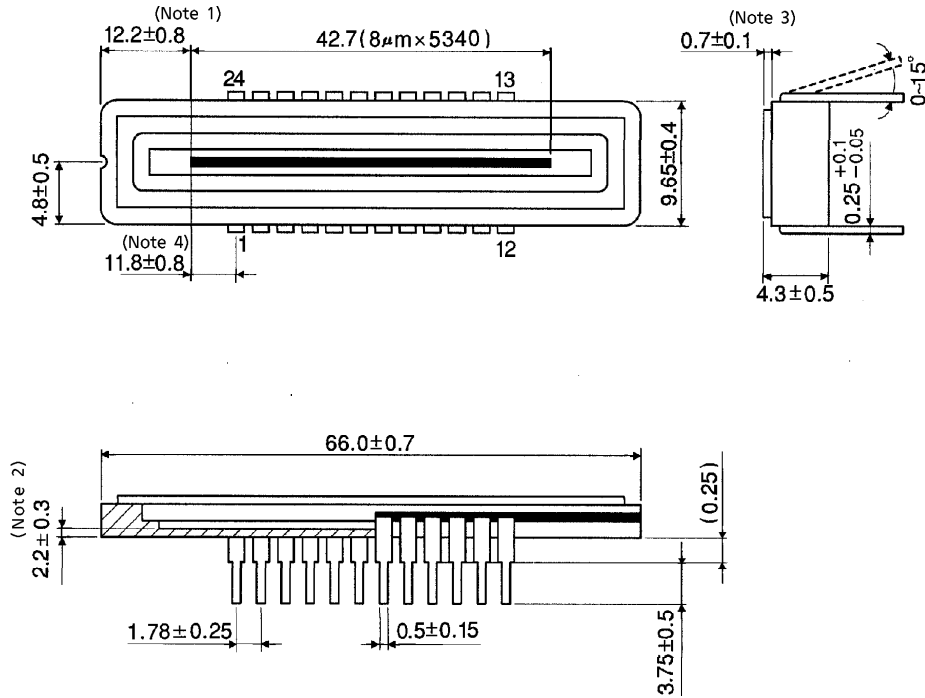
Since this package is not strong against mechanical stress, you should not reform the lead frame.

We recommend to use a IC-inserter when you assemble to PCB.

OUTLINE DRAWING

WDIP24G-400-1.78 (B)

Unit : mm



- (Note 1) : No. 1 SENSOR ELEMENT (S1) TO EDGE OF PACKAGE.
- (Note 2) : TOP OF CHIP TO BOTTOM OF PACKAGE.
- (Note 3) : GLASS THICKNESS (n = 1.5)
- (Note 4) : No. 1 SENSOR ELEMENT (S1) TO EDGE OF NO. 1 PIN.

Weight : 8.0 g (Typ.)